



NSAI
Standards

Irish Standard
I.S. EN 62132-8:2012

Integrated circuits - Measurement of electromagnetic immunity -- Part 8: Measurement of radiated immunity - IC stripline method (IEC 62132-8:2012 (EQV))

I.S. EN 62132-8:2012

Incorporating amendments/corrigenda issued since publication:

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EUROPEAN STANDARD
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EUROPÄISCHE NORM

EN 62132-8

September 2012

ICS 31.200

English version

**Integrated circuits -
Measurement of electromagnetic immunity -
Part 8: Measurement of radiated immunity -
IC stripline method
(IEC 62132-8:2012)**

Circuits intégrés -
Mesure de l'immunité électromagnétique -
Partie 8: Mesure de l'immunité rayonnée -
Méthode de la ligne TEM à plaques pour
circuit intégré
(CEI 62132-8:2012)

Integrierte Schaltungen -
Messung der elektromagnetischen
Störfestigkeit -
Teil 8: Messung der Störfestigkeit bei
Einstrahlungen -
IC-Streifenleiterverfahren
(IEC 62132-8:2012)

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CENELEC

European Committee for Electrotechnical Standardization
Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

Management Centre: Avenue Marnix 17, B - 1000 Brussels

I.S. EN 62132-8:2012

EN 62132-8:2012

- 2 -

Foreword

The text of document 47A/882/FDIS, future edition 1 of IEC 62132-8, prepared by SC 47A, "Integrated circuits", of IEC TC 47, "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62132-8:2012.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2013-05-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2015-08-10

This standard is to be used in conjunction with EN 62132-1.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

Endorsement notice

The text of the International Standard IEC 62132-8:2012 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050	Series	International Electrotechnical Vocabulary	-	-
IEC 61000-4-20	2010	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN 61000-4-20	2010
IEC 62132-1	2006	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 62132-1 + corr. November	2006 2006

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CONTENTS

FOREWORD	4
1 Scope	6
2 Normative references	6
3 Terms and definitions	6
4 General	7
5 Test conditions	7
5.1 General	7
5.2 Supply voltage	8
5.3 Frequency range	8
6 Test equipment	8
6.1 General	8
6.2 Cables	8
6.3 Shielding	8
6.4 RF disturbance generator	8
6.5 IC stripline	8
6.6 50 Ω termination	8
6.7 DUT monitor	8
7 Test setup	9
7.1 General	9
7.2 Test configuration	9
7.3 EMC test board (PCB)	9
8 Test procedure	9
8.1 General	9
8.2 Operational check	10
8.3 Immunity measurement	10
8.3.1 General	10
8.3.2 RF disturbance signal	10
8.3.3 Test frequency steps and ranges	10
8.3.4 Test levels and dwell time	10
8.3.5 DUT monitoring	10
8.3.6 Detail procedure	11
9 Test report	11
10 RF immunity acceptance level	11
Annex A (normative) Field strength determination	12
Annex B (normative) IC stripline descriptions	15
Annex C (informative) Closed stripline geometrical limitations	18
Bibliography	22
Figure 1 – IC stripline test setup	9
Figure A.1 – Definition of height (h) and width (w) of IC stripline	12
Figure A.2 – EM field distribution	13
Figure B.1 – Cross section view of an example of an open IC stripline	15
Figure B.2 – Cross section view of an example of a closed IC stripline	16

I.S. EN 62132-8:2012

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– 3 –

Figure B.3 – Example of IC stripline with housing	17
Figure C.1 – Calculated H -field reduction of closed version referenced to referring open version as a function of portion of active conductor width of closed version to open version	20
Figure C.2 – Location of currents and mirrored currents at grounded planes used for calculation of fields	21
Table 1 – Frequency step size versus frequency range	10
Table B.1 – Maximum DUT dimensions for 6,7 mm IC stripline (Open version)	16
Table B.2 – Maximum DUT dimensions for 6,7 mm IC stripline (Closed version)	16
Table C.1 – Height of shielding, simulated at $h_{\text{bottom}} = 6,7\text{mm}$ to achieve practically 50 Ω system	19

INTERNATIONAL ELECTROTECHNICAL COMMISSION

INTEGRATED CIRCUITS – MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –

Part 8: Measurement of radiated immunity – IC stripline method

FOREWORD

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International Standard IEC 62132-8 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/882/FDIS	47A/886/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

A list of all the parts in the IEC 62132 series, published under the general title *Integrated circuits – Measurement of electromagnetic immunity*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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